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## NTE5567, NTE5568, NTE5569, & NTE5571 Silicon Controlled Rectifier (SCR) 80 Amp ( $I_{T(RMS)}$ ), TO65 (TO208AC)

### Features:

- High Current Rating
- Excellent Dynamic Characteristics
- Superior Surge Capabilities
- Standard Package

### Voltage Ratings and Electrical Characteristics: ( $T_J = +125^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions		Values	Unit
Maximum Repetitive Peak Forward & Reverse Voltage NTE5567	$V_{DRM}, V_{RRM}$	Note 1		200	V
NTE5568				600	V
NTE5569				1200	V
NTE5571				1600	V
Maximum Non-Repetitive Peak Voltage NTE5567	$V_{RSM}$	Note 2		300	V
NTE5568				700	V
NTE5569				1300	V
NTE5571				1700	V
Peak Reverse & Off-State Current	$I_{DRM}, I_{RRM}$			15	mA
Average On-State Current NTE5567, NTE5568, NTE5569	$I_{T(AV)}$	180° Sinusoidal Conduction	$T_C = +94^\circ\text{C}$	50	A
NTE5571			$T_C = +90^\circ\text{C}$	50	A
RMS On-State Current	$I_{T(RMS)}$			80	A
Peak One-Cycle Non-Repetitive Surge Current	$I_{TSM}$	t = 10ms, No Voltage Reapplied, Sinusoidal Half Wave		1200	A
$I^2t$ for Fusing NTE5567, NTE5568, NTE5569	$I^2t$	t = 10ms, Sinusoidal Half Wave	No Voltage Reapplied	10.18	KA <sup>2</sup> s
				7.21	KA <sup>2</sup> s
			100% $V_{RRM}$ Reapplied	7.20	KA <sup>2</sup> s
				5.10	KA <sup>2</sup> s

Note 1. Units may be broken over non-repetitively in the off-state direction without damage, if di/dt does not exceed 20A/ $\mu\text{s}$ .

Note 2. For voltage pulses with  $t_p \leq 5\text{ms}$ .

**Voltage Ratings and Electrical Characteristics (Cont'd):** ( $T_J = +125^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Values	Unit
$I^2t$ for Fusing NTE5567, NTE5568, NTE5569	$I^2t$	t = 0.1 to 10ms, No Voltage Reapplied	10.18	KA <sup>2</sup> v/s
NTE5571			7.21	KA <sup>2</sup> v/s
Low Level Value of Threshold Voltage NTE5567, NTE5568, NTE5569	$I_{T(TO)}$	16.7% $\times \pi \times I_{T(AV)} < I < \pi \times I_{T(AV)}$	0.94	V
NTE5571			1.02	V
High Level Value of Threshold Voltage NTE5567, NTE5568, NTE5569	$I_{T(TO)2}$	$\pi \times I_{T(AV)} < I < 20 \times \pi \times I_{T(AV)}$	1.08	V
NTE5571			1.17	V
Low Level Value of On–State Slope Resistance NTE5567, NTE5568, NTE5569	$r_{T1}$	16.7% $\times \pi \times I_{T(AV)} < I < 20 \times \pi \times I_{T(AV)}$	4.08	m $\Omega$
NTE5571			4.78	m $\Omega$
High Level Value of On–State Slope Resistance NTE5567, NTE5568, NTE5569	$r_{T2}$	$\pi \times I_{T(AV)} < I < 20 \times \pi \times I_{T(AV)}$	3.34	m $\Omega$
NTE5571			3.97	m $\Omega$
Maximum On–State Voltage NTE5567, NTE5568, NTE5569	$V_{TM}$	$I_{pk} = 157A, T_J = +25^\circ\text{C}$	1.60	V
NTE5571			1.78	V
Maximum Holding Current	$I_H$	$T_J = +25^\circ\text{C}$ , Anode Supply 22V, Resistive Load, Initial $I_T = 2A$	200	mA
Latching Current	$I_L$	Anode Supply 6V, Resistive Load	400	mA
Maximum Rate of Rise of Turned–On Current NTE5567, NTE5568,	di/dt	$V_{DM} = \text{Rated } V_{DRM}$ , Gate Pulse = 20V, 15 $\Omega$ , $t_p = 6\mu\text{s}$ , $t_r = 0.1\mu\text{s}$ Max, $I_{TM} = (2 \times \text{Rated } di/dt) A$	200	A/ $\mu\text{s}$
NTE5569, NTE5571			100	A/ $\mu\text{s}$
Typical Delay Time	$t_d$	$T_C = +25^\circ\text{C}$ , $V_{DM} = \text{Rated } V_{DRM}$ , DC Resistive Circuit, Gate Pulse = 10V, 15 $\Omega$ Source, $t_p = 20\mu\text{s}$	0.9	$\mu\text{s}$
Typical Turn–Off Time	$t_q$	$T_C = +125^\circ\text{C}$ , $I_{TM} = 50A$ , Reapplied dv/dt = 20V/ $\mu\text{s}$ , dir/dt = 10A/ $\mu\text{s}$ , $V_R = 50V$	110	$\mu\text{s}$
Maximum Critical Rate of Rise of Off–State Voltage	dv/dt	Linear to 100% Rated $V_{DRM}$	200	V/ $\mu\text{s}$
		Linear to 67% Rated $V_{DRM}$	500	V/ $\mu\text{s}$
Maximum Peak Gate Power	$P_{G(AV)}$	$t_p \leq 5\text{ms}$	10	W
Maximum Average Gate Power	$P_{GM}$		2.5	W
Maximum Peak Positive Gate Current	$I_{GM}$		2.5	A
Maximum Peak Positive Gate Voltage	+ $V_{GM}$		10	V
Maximum Peak Negative Gate Voltage	- $V_{GM}$		10	V
DC Gate Current Required to Trigger	$I_{GT}$	6V, Anode–to–Cathode Applied	100	mA
DC Gate Voltage Required to Trigger	$V_{GT}$	6V, Anode–to–Cathode Applied, $T_J = +25^\circ\text{C}$	2.5	V
DC Gate Current Not to Trigger	$I_{GD}$	Rated $V_{DRM}$ , Anode–to–Cathode Applied	5.0	mA

Note 1. Units may be broken over non–repetitively in the off–state direction without damage, if di/dt does not exceed 20A/ $\mu\text{s}$ .

Note 2. For voltage pulses with  $t_p \leq 5\text{ms}$ .

**Voltage Ratings and Electrical Characteristics (Cont'd):** ( $T_J = +125^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Values	Unit
DC Gate Voltage Not to Trigger	$V_{GD}$	Rated $V_{DRM}$ , Anode-to-Cathode Applied	0.2	V
Operating Junction Temperature Range	$T_J$		-40 to +125	$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$		-40 to +125	$^\circ\text{C}$
Thermal Resistance, Junction-to-Case	$R_{thJC}$	DC Operation	0.35	K/W
Thermal Resistance, Case-to-Heatsink	$R_{thCS}$	Mounting Surface Smooth, Flat, and Greased	0.25	K/W
Mounting Torque	T	Non-Lubricated Threads	2.8	Nm

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Note 2. For voltage pulses with  $t_p \leq 5\text{ms}$ .

